Applicant(s)/Patent Under Application/Control No. Reexamination 10/509,433 **CHON ET AL** Notice of References Cited Examiner Art Unit Page 1 of 1 David Vu 2821 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,049,171 04-2000 Stam et al. 315/82 Α US-5,998,929 12-1999 Bechtel et al. 315/82 В US-С US-D US-Ε US-F US-G US-Н US-US-US-K US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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